

DEVICE MANAGEMENT METHOD, ANALYSIS SYSTEM USED THEREIN,
MAINTENANCE INSPECTION SUPPORT METHOD, AND MAINTENANCE
INSPECTION SUPPORT APPARATUS USED THEREIN

ABSTRACT

A complete test involving the entire number of devices in a large group of managed devices (T) is periodically performed to determine whether the devices are operating normally or have a malfunction; a test result (Ic) is recorded in a management database (Db) for each cycle of the complete test, and a device that has been found to be malfunctioning is repaired or replaced; and the suitability of a device model is determined or a suitable device model is selected for each of the managed devices (T) on the basis of history information (N) about each of the managed devices (T) obtained from the test result (Ic) of the complete test that spans a plurality of cycles, as recorded in the management database (Db).

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